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Applicants: Takuji HIMENO et al.

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For: IMAGE DATA PROCESSING APPARATUS AND

**METHOD** 

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Enclosed are copies of the publications, which were cited in the International Search Report of International Application No. PCT/JP03/08432. Also enclosed is a copy of Form PTO-1449 and the International Search Report.

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## **REMARKS**

Entry of this Information Disclosure Statement and an early examination on the merits are respectfully solicited.

Please charge any additional fees to Deposit Account No. 50-0320.

Respectfully submitted,

FROMMER LAWRENCE & HAUG LLP Attorneys for Applicants

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**Enclosures** 

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Sheet 1 of 1

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